

About this brochure

Explore our industry-leading portfolio of optical testing solutions for manufacturing and laboratory applications.

This brochure provides an overview of our comprehensive range of optical testing solutions including component test platforms, light sources, benchtop tunable lasers, passive component testers, optical spectrum analyzers, tunable filters with adjustable bandwidth, variable attenuators, switches and power meters.

Reach out to us to benefit from best-in-class products and from 35+ years of expertise and dedicated customer service.

About EXFO

EXFO develops smarter test, monitoring and analytics solutions for the global communications industry. We are trusted advisers to fixed and mobile network operators, hyperscalers and leaders in the manufacturing, development and research sector. They count on us to deliver superior visibility and insights into network performance, service reliability and user experience. Building on our 35 years of innovation, EXFO's unique blend of equipment, software and services enable faster, more confident transformations related to 5G, cloud-native and fiber optic networks.

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Optical spectrum analyzer

The OSA20 is the industry's most advanced optical spectrum analyzer for R&D and manufacturing.

Fast

The fastest OSA of its kind with a maximum sweep speed of 2000 nm/s.

High performance

The OSA20 features a state-of-the-art monochromator that yields a resolution bandwidth of 20 pm, steep edges and low stray light. This allows for full analysis of even extremely complex signals such as novel modulation formats, superchannels, flex-grid and DWDM signals down to 12.5 GHz spacing. Moreover, the instrument has a high wavelength accuracy over the full wavelength range with ± 10 pm specified over 1500-1640 nm.

User-friendly interface

Navigation, scrolling and zooming using an intuitive 12-in color touchscreen, an industry first.

Target application analysis

Select from 8 different analysis modes available as standard:

OSA Optical spectrum analyzer for general purpose analysis

WDM Wavelength division multiplexing for CWDM or DWDM analysis

OFA Optical fiber amplifier for EDFAs, SOAs, etc.

SML Singlemode laser for DFB Lasers and external cavity lasers

MML Multilongitudinal mode laser for Fabry-Perot lasers

BBS Broadband source for SLEDs and fiber-based ASE sources
PCT Passive component test for couplers and thin-film filters

RLT Recirculating loop transmission for longhaul system evaluation



- Scan speed: up to 2000 nm/s
- Wavelength range: 1250-1700 nm
- Resolution bandwidth:
 - 20 pm native
 - Adjustable over 50-2000 pm
- Wavelength accuracy:
 - ±10 pm over 1500-1640 nm
 - ±25 pm over 1250-1700 nm
- Sampling resolution: 2 pm
- Modern interfaces

Component test platform

The CTP10 is a modular measurement platform for efficient testing of high port-count passive components in 24/7 operation. The CTP10 works with one or several of EXFO's sweeping tunable lasers to provide swept insertion loss (IL), polarization dependent loss (PDL) and return loss (RL) measurements with unprecedented performance in the industry.

Highest specifications at full speed

The CTP10 maintains industry-leading specifications even when used with a laser at 100 nm/s. You no longer have to compromise between speed and measurement accuracy as the CTP10 provides a 70-dB dynamic range in a single scan together with a 1-pm sampling resolution even at 100 nm/s.

The CTP10 is the ideal instrument to characterize advanced WDM components with high port-count, such as wavelength selective switches (WSS). It is also particularly well suited for optical testing of photonic integrated circuit (PIC), both in R&D and manufacturing environments.

Next-gen platform and modules

The following modules are available:

IL RL OPM2 Insertion loss and return loss module with two optical detectors

IL PDL Insertion loss and polarization dependent loss module in C+L telecom bands

IL PDL OPM2 Insertion loss and polarization dependent loss module operating across CTP10 spectral range

and with two optical detectors

SCAN SYNC Optical sampling of swept wavelength lasers

OPMx Optical detector module with 2, 4 or 6 detectors

FBC & FBC-M Full-band combiner module for broadband swept measurements of IL & RL or IL & PDL, respectively

PCMx Photo-current meter module with 2 or 6 inputs

Powerful intuitive GUI

The embedded software offers a powerful and intuitive GUI to graphically configure the test setup, perform measurement and analysis.

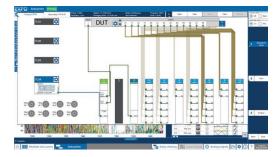
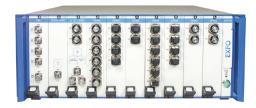


Figure 1. Configuration screen



- Wavelength range:1240-1680 nm
- Dynamic range: 70 dB in a single sweep
- IL resolution: 0.1 mdB
- Up to 50 detectors per platform
- Wavelength accuracy: ±5 pm
- Sampling resolution: 0.02 pm



Figure 2. Measurement screen

Passive component tester

The CT440 is a versatile instrument for performing swept IL-PDL measurements of passive optical components. It works together with EXFO's line of sweeping tunable lasers to provide a 65-dB dynamic range with a wavelength accuracy of ± 5 pm. The CT440 is provided with a GUI software for direct operation from a PC.

Five CT440 models are available for various applications:

Model	Wavelength range	Measurement	DUT type
CT440-SMF	1240-1680 nm	IL	SMF
CT440-PM13	1260-1360 nm	IL	PMF
CT440-PM15	1440-1640 nm	IL	PMF
CT440-PDL-PM13	1260-1360 nm	IL, PDL	SMF
CT440-PDL-PM15	1440-1640 nm	IL, PDL	SMF



- Wavelength range: 1240 1680 nm
- Dynamic range in a single sweep: 65 dB
- Sampling resolution: 1 pm (even at 100 nm/s)
- Wavelength accuracy: ±5 pm
- Up to 4 detectors
- The SMF model operates over the full band and performs IL measurements.
 Up to 4 lasers can be connected for seamless full-band swept measurements.
- The PM model offers a complete solution to characterize components with polarization-maintaining fiber.
- The PDL model is a turnkey solution for swept IL and PDL measurements.

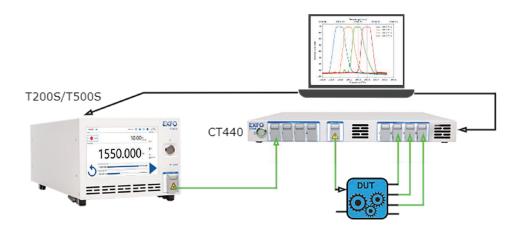


Figure 3. Typical measurement configuration using the CT440 component tester with a T200S/T500S tunable laser

Benchtop tunable lasers

The T200S and T500S constitute the most advanced and cost-effective solution for all R&D and manufacturing environments.

These lasers can be used as part of a swept test system together with the CTP10 or CT440 component tester for swept IL, RL and PDL measurements. As an alternative, both lasers can be used as standalone lasers in stepped mode.

Models available

The T200S portfolio features 2 models:

The /O and /CL lasers deliver 10 dBm of output power and are mainly dedicated to telecom applications.

The T500S portfolio features 5 models:

The /O, /ES, /SCL, /CL and /CLU lasers can be adjusted from 10 dBm to maximum available optical power of 13 dBm across specific wavelength ranges.

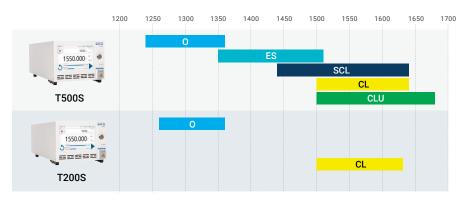


Figure 4. Spectral coverage of the various T200S-T500S models

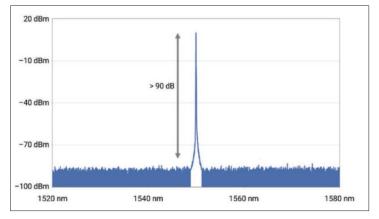


Figure 5. High power and high dynamic range



- Power: 10+ dBm (T500S) and 10 dBm (T200S)
- Tuning range: up to 180 nm
- Tuning speed: 200 nm/s
- Bidirectional sweep (T500S)
- Wavelength accuracy: ±5 pm typical
- < 50 kHz linewidth
- Sweeping and stepping operation
- Full-band coverage with 3 lasers (T500S)
- Signal to noise ratio: 100 dB
- Compatible with the CTP10 and CT440 component testers
- Ethernet port

Tunable filters

The XTA-50 and XTM-50 are wavelength tunable and bandwidth adjustable filters. The use of bulk optics in combination with diffraction gratings leads to high selectivity, low insertion losses and dispersion. Thanks to the adjustable bandwidth and very steep edges, the XT filters are a reference for precise filtering of a channel or even of a subdivision of a channel.

Models available

Model	Wavelength range	Bandwidth	Slope
Standard	1450-1650 nm	50-950 pm (6.25-120 GHz)	500 dB/nm
Ultrafine	1480-1620 nm	32-650 pm (4-80 GHz)	800 dB/nm
Wide	1525-1610 nm	50-5000 pm (6.25-625 GHz)	350-500 dB/nm
O-band	1260-1360 nm	50-900 pm (8-160 GHz)	500 dB/nm

Manual and automated versions

XTA-50 Automated wavelength tuning and bandwidth adjustment

XTM-50 Manual wavelength tuning and bandwidth adjustment

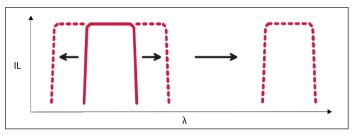


Figure 6. Bandwidth and wavelength tuning

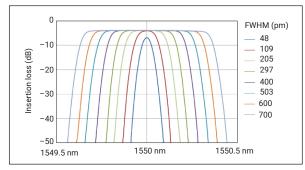


Figure 7. Bandwidth tuning



Key features

- Wavelength and bandwidth adjustable
- Manual (XTM-50) and automated (XTA-50) versions
- IL: < 5 dB
- Sharp roll-off
- SMF and PMF versions
- O-band model available

Glossary

IL: insertion loss

RL: return loss

SMF: singlemode fiber

PMF: polarization-maintaining optical fiber

Modular optical test solutions

Compatible with both rackmount and portable platforms, EXFO's modular optical test solutions were meticulously engineered to optimize the testing of a variety of technologies and ensure simplicity and efficiency in laboratory settings. Test solutions cover photonic integrated circuits (PICs), WSS, ROADM, passive optical components and more.

Rackmount platforms



LTB-2, LTB-8 and LTB-12

Rackmount modular test platforms with 2, 8 or 12 slots

Portable platforms





FTB-1v2, FTB-2 Pro and FTB-4 Pro

Portable modular test platforms with 1, 2 or 4 slots

Power meter



FTBx-1750

High performance power meter (1-slot module)

Light sources



FTBx-2250

Broadband light source (1-slot module)



FTBx-2850

µITLA tunable light source (1-slot module)

Variable attenuators



FTBx-3500

Variable attenuator (1-slot module)



MOA-3800

Variable optical attenuator (rackmount)

Switches



FTBx-9160

MEMS optical switch (1-slot module)



MXS-9100

MEMS matrix optical switch (rackmount)

Optical spectrum analyzers



FTBx-5245

Optical spectrum analyzer (2-slot module)



FTBx-5243-HWA

High wavelength accuracy OSA (3-slot module)



FTBx-5255

High-end OSA – (2-slot module)



